
PRODUCT CHANGE NOTICE

Manufacturing Site Change for Assembly of Intersil Ceramic Solder Seal Packaged Products

**Refer to:
PCN11042**

Date: April 8, 2011

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To: Our Valued Intersil Customer

Subject: **Manufacturing Site Change for Assembly of Intersil Ceramic Solder Seal Packaged Products** – Amkor (ATP) Muntinlupa City, Philippines and Intersil (ISP) Palm Bay, FL

This notice is to inform you that Intersil is qualifying the Amkor (ATP) and Intersil (ISP) facilities for performing assembly of the listed Ceramic Leadless Chip Carrier (CLCC), Ceramic Solder Seal Flatpack (CFP), and Ceramic Solder Seal Dual-In-Line (SBDIP) packaged products. This action will provide the capability and capacities for Intersil to meet customer's delivery requirements. The product and site-specific qualification activities at ATP are in progress and expected to complete during the next three to six months. The ISP facility is considered QBE (Qualified by Extension) as the existing package styles, processes, and materials used to assemble the affected products are qualified and in use in on-going manufacturing operations at the facility today.

Products affected:

5962-0620701Q3A	5962-85016023A	5962-88502012A	84065013A
5962-0620702Q3A	5962-8512704XA	5962-8869002JA	84065023A
5962-0620703Q2A	5962-85131013A	5962-89620012A	8406602XA
5962-0620704Q2A	5962-85131013AS2035	5962-89635012A	85015013A
5962-0620705Q3A	5962-85131023A	5962-89636012A	HA4-5002/883
5962-0620706Q3A	5962-85131073A	5962-9306301M2A	HI1-565ASD/883
5962-0620707Q2A	5962-85131092A	5962-9467701M2A	HI1-674ATD/883
5962-0620708Q2A	5962-86716012A	77052012A	HI4-0546/883
5962-0623501QPC	5962-86860012A	7705201EC	HI4-0547/883
5962-0623502QPC	5962-8687901EA	77052022A	HI4-0548/883
5962-0623601QPC	5962-87677012A	78029013A	HI4-5051/883
5962-0623602QPC	5962-87677012AR4573	81006122A	HM1-6617/883
5962-0625501QXC	5962-87784012A	81006222A	HM1-6642B/883

The Amkor (ATP) and Intersil (ISP) facilities are ISO 9001:2008, TS 16949:2009, ISO 14001:2004, and currently QML Class Q certified assembly/test locations. The ATP facility is currently Intersil qualified for performing assembly operations for various package styles. The ISP facility is currently qualified for performing assembly operations for various package styles including the ceramic solder seal packages (CLCC, CFP, SBDIP) affected by this notice. There will be no change to the POD (package outline drawing), bond wire material, die attach material, package body, package lid, or final plating. The material set combinations for ceramic solder seal package assembly are as follows:

Material	CFP	CLCC/SBDIP	
Die Attach	Silver Polymer/ JM7000	Silver Polymer/ JM7000	Gold Eutectic
Bond Wire	1.25 mil Aluminum (Al)		
Seal	Gold-Tin (AuSn) Solder		

The assembly qualification plan for the ATP facility is designed using MIL-PRF-38535, JEDEC, and other applicable industry standards to confirm there is no impact to form, fit, function, or interchangeability of the product. A summary of the ATP qualification plan is included. The ISP facility is considered QBE (Qualified by Extension) as the existing package styles, processes, and materials used to assemble the affected products are qualified and in use in on-going manufacturing operations at the facility today. The remainder of the manufacturing operations (wafer fabrication, package level electrical testing, shipment, etc.) will continue to be processed to previously established conditions and systems.

Product affected by this change is identifiable via Intersil's internal traceability system. In addition, product assembled at ATP and ISP may be identified by the assembly site code (country of assembly) when marked on the devices. The site code for product assembled at ATP is "L" and ISP is "X".

Intersil will take all necessary actions to conform to agreed upon customer requirements and to ensure the continued high quality and reliability of Intersil products being supplied. Customers may expect to receive product assembled at either the current or ISP sites beginning immediately and the ATP site upon completion of qualification activities.

If you have concerns with this change notice, Intersil must hear from you promptly. Please contact the nearest Intersil Sales Office or call the Intersil Corporate line at 1-888-468-3774, in the United States, or 1-321-724-7143 outside of the United States.

Regards,



Jon Brewster
Intersil Corporation

PCN11042

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PCN11042 – ATP Qualification Plan

Reliability Test	5962-8512704XA	5962-85131013A	HI1-565ASD/883
	28 LEAD SBDIP - POLYMER/JM7000	28 LEAD CLCC - POLYMER/JM7000	24 LEAD SBDIP - Eutectic
Subgroup B1	ss=3 from 1 lot	ss=3 from 1 lot	ss=3 from 1 lot
	Resistance to Solvents. MIL-PRF-38535 Group B Test Method 2015	Resistance to Solvents. MIL-PRF-38535 Group B Test Method 2015	Resistance to Solvents. MIL-PRF-38535 Group B Test Method 2015
Subgroup B2	ss=3 from 1 lot	ss=3 from 1 lot	ss=3 from 1 lot
	Die Shear Test or Stud Pull. MIL-PRF-38535 Group B Test Method 2019 or 2027	Die Shear Test or Stud Pull. MIL-PRF-38535 Group B Test Method 2019 or 2027	Die Shear Test or Stud Pull. MIL-PRF-38535 Group B Test Method 2019 or 2027
	ss=4 from 1 lot	ss=4 from 1 lot	ss=4 from 1 lot
	Wire Bond strength. MIL-PRF-38535 Group B Test Method 2011. 22 wires from 4 devices	Wire Bond strength. MIL-PRF-38535 Group B Test Method 2011. 22 wires from 4 devices	Wire Bond strength. MIL-PRF-38535 Group B Test Method 2011. 22 wires from 4 devices
Subgroup B3	ss=22 from 1 lot	ss=22 from 1 lot	ss=22 from 1 lot
	Solderability Lead Finish. MIL-PRF-38535 Group B Test Method 2003	Solderability Lead Finish. MIL-PRF-38535 Group B Test Method 2003	Solderability Lead Finish. MIL-PRF-38535 Group B Test Method 2003

PCN11042 – ATP Qualification Plan – cont.

Reliability Test	5962-8512704XA	5962-85131013A	HI1-565ASD/883
	28 LEAD SBDIP - POLYMER/JM7000	28 LEAD CLCC - POLYMER/JM7000	24 LEAD SBDIP - Eutectic
Subgroup D1	ss=15 from 1 lot	ss=15 from 1 lot	ss=15 from 1 lot
	a) Physical Dimensions	a) Physical Dimensions	a) Physical Dimensions
Subgroup D2	ss=15 from 1 lot	ss=15 from 1 lot	ss=15 from 1 lot
	a) Lead Integrity	a) Lead Integrity	a) Lead Integrity
Subgroup D2	b) Seal Test (Fine & Gross Leak)	b) Seal Test (Fine & Gross Leak)	b) Seal Test (Fine & Gross Leak)
Subgroup D3	ss=15 from 1 lot	ss=15 from 1 lot	ss=15 from 1 lot
	a) Thermal Shock	a) Thermal Shock	a) Thermal Shock
	b) Temp Cycle (100)	b) Temp Cycle (100)	b) Temp Cycle (100)
	c) Moisture Resist	c) Moisture Resist	c) Moisture Resist
	d) Visual Inspection	d) Visual Inspection	d) Visual Inspection
	e) Seal Test (Fine & Gross Leak)	e) Seal Test (Fine & Gross Leak)	e) Seal Test (Fine & Gross Leak)
Subgroup D4	f) Electrical	f) Electrical	f) Electrical
	ss=15 from 1 lot	ss=15 from 1 lot	ss=15 from 1 lot
	a) Mechanical Shock	a) Mechanical Shock	a) Mechanical Shock
	b) Vibration	b) Vibration	b) Vibration
	c) Constant Acc.	c) Constant Acc.	c) Constant Acc.
	d) Seal Test (Fine & Gross Leak)	d) Seal Test (Fine & Gross Leak)	d) Seal Test (Fine & Gross Leak)
Subgroup D5	e) Visual Inspection	e) Visual Inspection	e) Visual Inspection
	f) Electrical	f) Electrical	f) Electrical
	ss=15 from 1 lot	ss=15 from 1 lot	ss=15 from 1 lot
Subgroup D5	a) Salt Atmosphere	a) Salt Atmosphere	a) Salt Atmosphere
	b) Visual Inspection	b) Visual Inspection	b) Visual Inspection
	c) Seal Test (Fine & Gross Leak)	c) Seal Test (Fine & Gross Leak)	c) Seal Test (Fine & Gross Leak)
Subgroup D6	ss=3 from 1 lot	ss=3 from 1 lot	ss=3 from 1 lot
	Internal Water Vapor	Internal Water Vapor	Internal Water Vapor
Subgroup D7	ss=15 from 1 lot	Not Applicable no leads	ss=15 from 1 lot
	Adhesion of Lead Finish		Adhesion of Lead Finish
Subgroup D8	Not required for solder seal parts	Not required for solder seal parts	Not required for solder seal parts